

Computing WFIRST weak lensing requirements on detector calibration

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Requirements for the WFIRST NIR detectors flow from the science requirements of the cosmology and exoplanet surveys. Detector requirements for WFIRST weak gravitational lensing have been studied by

Detector Working Group (co-leads D. Bennet, C. Shapiro) Cosmology Science Investigation Team (PI: O. Doré)

<u>Outline</u>

- WFIRST recap
- Nonlinearity Andrés Plazas-Malagon (JPL)
- Interpixel Capacitance Arun Kannawadi (Carnegie Mellon → Leiden)
- Persistence Eric Huff (JPL)

WFIRST Imager overview

- 2.4m telescope
- f/8 imager (Wide Field Channel)
- 18x Hawaii-4RG detectors 4kx4k pixels; 10μm pixel pitch
- Plate scale 0.11"/pixel
- Field of view (FOV) 0.8° x 0.4°
- Near-infrared pass band: 0.76 2.3μm
- 6 (7?) imaging filters
- 5-9 dithers/source/filter (images are undersampled)







Band	Element name	Min (μm)	Max (µm)	Center (µm)	Width (μm)	R
Z	Z087	0.76	0.977	0.869	0.217	4
Y	Y106	0.927	1.192	1.060	0.265	4
J	J129	1.131	1.454	1.293	0.323	4
н	H158	1.380	1.774	1.577	0.394	4
	F184	1.683	2.000	1.842	0.317	5.81
Wide	W149	0.927	2.000	1.485	1.030	1.44
GRS	Grism	1.0*	1.89*	1.445	0.890	461λ(2pix)

Slide adapted from WFIRST Project report

Observatory Reference Information

WFIRST galaxy shape measurement requirements

- Baseline: 2000 deg² with 45 galaxies/arcmin²
- Extended mission: 10k deg²
- (Nominal) knowledge requirements for shear measurement error: δg_i = (1+m)g_i + c
 Multiplicative error: m ~ 0.001
 Additive error: c ~ 0.0003
- PSF knowledge requirements (rms): c \rightarrow Ellipticity ~ 0.0005 ; m \rightarrow Size (d σ/σ) ~ 0.0009
- Images are undersampled in J, H, F184 bands



Image: GREAT08 Handbook

The effect of detector nonlinearity on WFIRST PSF profiles for weak gravitational lensing measurements

<u>A. A. Plazas</u>, C. Shapiro, A. Kannawadi, R. Mandelbaum, J. Rhodes, & R. Smith (arXiv:1605.01001. Submitted to PASP)

Nonlinearity in the signal chain



Image credit: R. Smith

NL in hybrid CMOS detectors



- If the main source of nonlinearity is the junction capacitance, the correction to the inferred signal is wellapproximated by a quadratic function
- Additional parameters can improve calibration but are highly degenerate we stick with 1 for simplicity

$$S(Q) = Q - \beta Q^2$$

 β ~ 5e-7 (WFC3, Hilbert 2014), varies per pixel and detector

Image simulations with GalSim









NL depresses PSF peak \rightarrow size measurement bias

No ellipticity bias unless PSF has |e|>0 (it does)

- We use the WFIRST module (Kannawadi +15) in GalSim (Project-funded) to simulate PSF profiles for WFIRST bands J, Y, H, F
- Pixel scale = 0.11 arcsec/pixel; images are drawn at 3x resolution to mimic reconstruction from dithers (avoids aliasing)
- Centroids randomized within native pixel
- Considered AB magnitudes down to 18.3, which fills a H4RG pixel to 90% of full well (~1.1k e⁻) in 168 seconds (Y band, PSF centered on a pixel)
- NL applied to each pixel according to:

 $I \mapsto I - \beta I^2$

PSF size and shape measurements

- For weak lensing, the PSF sampled from nearby bright stars (affected more by NL) must be deconvolved from observed galaxy shapes
- The error in the galaxy ellipticity measurement is given by a linear combination of fractional PSF size error and absolute PSF ellipticity error (e.g, Paulin-Henriksson et al. 2008, Massey et al. 2013)
- Nominal WFIRST error tolerances:

 $\Delta e_i \equiv e_i - e_{i,0}, \quad i \in [1,2]$

- relative size to ~ 1e-3 ; absolute ellipticity to ~4.5e-4
- We use adaptive moments (HSM method) to measure

 $\frac{\Delta R}{R} \equiv \frac{R - R_0}{R_0}$

PSF size (*R*) and ellipticity (e_i) before and after NL is applied.

					Total signal	Center pixel			"R"
	Band	Min. λ	Max. λ	$\lambda_{ ext{eff}}$	$b(\lambda)$	peak value	e ₁	e ₂	σ (pix)
Baseline	Dand	(μm)	(μm)	(μm)	$(\times 10^5) (e^-)$	$(\times 10^5) (e^-)$	(#18)	(#18)	(#18)
WFIRST	Y106	0.900	1.230	1.061	2.7621	1.00237	-0.0163	0.2035	1.7020
PSFs	J129	1.095	1.500	1.292	2.8267	0.89742	-0.0127	0.1325	1.717
1 51 5	H158	1.340	1.830	1.577	2.7922	0.38654	-0.0089	0.0802	1.832
	F184	1.630	2.060	1.837	1.8346	0.71890	-0.0071	0.0550	1.995

Biases in size and ellipticity (uncorrected for NL)



Since errors are approximately linear in β , we can condense information by plotting the slope of each curve as a function of magnitude.

 $\Delta R/R/eta$ $\Delta e/eta$

Biases in size and ellipticity after NL calibration

Replacing β with the error $\Delta\beta$, we can use this plot to convert between star magnitudes, PSF error tolerances, and calibration precision on β (given 2, predict the 3rd one)



$$rac{\Delta R/R}{\Delta eta} = c \quad \Rightarrow \quad rac{\Delta eta}{eta_0} = rac{\Delta R/R}{c eta_0}$$

For example, to use 18.3 mag stars (H-band) while limiting PSF biases to 10% of WFIRST tolerances, β must be known to ~1% for R ~2.4% for e_i

Assumption: β_0 =5e-7

→ Set requirements on $\Delta\beta$ or set mag cutoffs (or ramp cutoffs if sampling up the ramp)

Spatial variability of β

We then assume each pixel has a different β , drawn from a gaussian distribution. We plot stddev of PSF errors vs. stddev of β (M=100 realizations).



- Linearity in β allows us to condense information as before.
- Bias when NL is uncorrected is insensitive to the nominal β , so σ_{β} can also be interpreted as an error on β estimation

Interpixel Capacitance effects on weak lensing shape measurement

Arun Kannawadi (CMU), Charles Shapiro (JPL), Rachel Mandelbaum (CMU), Chris Hirata (OSU), Jeff Kruk (GSFC) & Jason Rhodes (JPL,Caltech)

Slide stolen from B. Rauscher



- I. Moore, A. C., Ninkov, Z. & Forrest, W. J. 2006, Optical Engineering, 45, 076402 describes the statistics in detail from a Fourier perspective
- 2. Fox, O., Waczynski, A., Wen, Y., et al. 2009, PASP, 121, 743 arrives at many of the same results working in the pixel domain

IPC effects on shape measurement

- Charge collected on a pixel induces voltage change on neighbor pixels; charge does not move
- Generally makes the PSF
 appear larger
- Isotropic IPC makes the PSF and galaxies appear rounder
- Anisotropic IPC induces
 spurious ellipticity
- IPC correlates shot noise
- Correcting IPC at the pixel level correlates read noise

Inter-pixel capacitance (IPC) in CMOS detectors



Idealized kernel showing fraction of central pixel's signal shared among neighbors

Assumed IPC model

3 degrees of freedom motivated from WFC3 measurement

- Isotropic nearest neighbors $\,\alpha\,$
- Isotropic diagonal neighbors $\, \alpha' \,$
- "+" anisotropy α_+

$$K_{\alpha,\alpha_{+},\alpha'} = \begin{pmatrix} \alpha' & \alpha - \alpha_{+} & \alpha' \\ \alpha + \alpha_{+} & 1 - 4(\alpha + \alpha') & \alpha + \alpha_{+} \\ \alpha' & \alpha - \alpha_{+} & \alpha' \end{pmatrix}$$

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Limitations of the model

- Ignoring other possible asymmetries
- Ignoring pixels beyond nearest neighbors
- Ignoring IPC variations across the detector.

Kernels measured for 3 WFIRST test detectors (WFIRST Project)

PSF simulations with IPC

- PSFs in J, H and F bands are simulated using the WFIRST module within GalSim. Assuming IPC is independent of fluence.
- PSFs include diffraction spikes and aberrations but not jitter, charge diffusion or other detector effects such as nonlinearity.
- To obtain oversampled images, "dithers" with uniform sub-pixel offsets are *interleaved* after drawing PSFs at native pixel scale (0.11"/px) and convolving with IPC kernel.
- PSF shapes are measured using adaptive moments (HSM method). Half-light radius is also measured.

Kannawadi et al. arXiv:1512.01570

Effect of uncorrected IPC on PSF size



X = Nominal IPC values

Worse effect at lower wavelengths as expected



Effect of uncorrected IPC on ellipticity of PSF

Kannawadi et al.

Effect of anisotropic IPC on PSF ellipticity



Shape measurement error from IPC calibration error

- Kannawadi et al. derives fitting formulae for propagating IPC error into shape errors.
- EXAMPLE: Suppose the IPC parameters are known to within absolute errors of δα=δα'=δα₊=10⁻⁴. Errors may be due to measurement or spatial variation. Modeling the WFIRST PSF with these errors, the worst PSF shape errors are in the J band: δσ/σ≈6e-4 and δe₁≈4e-4. Comparable to error budget.
- In practice, a PSF model will be fit to on-sky measurements, and IPC errors will be absorbed by other parameters in the PSF model.
- Ability to calibrate should not be taken for granted

Persistence

- Image contaminated by "echo" of previous exposure
- Mechanism: charges building up in traps during exposure; released over time (~minutes)
- Persistence amplitude and decay time vary by device as well as by pixel, exposure history, temperature, bias voltage, device age?
- Difficult to model may not be subtracted sufficiently for weak lensing. Flag pixels after exposures near full well.



WFC3 image showing persistence



Persistence in 2 WFIRST test devices, 10 min after 100ke- flats. Scale shows ~ order of magnitude variation

Analysis by Eric Huff (in progress): Treat persistent image as correlated noise

- Estimate noise power spectrum P(k) from Hubble Extreme Deep Field (XDF)
- Scale P(k) according to WFIRST persistence estimate
- Input P(k) to GalSim correlated noise generator and add to simulated galaxies



Drizzled XDF image

To model persistence, use measurements from WFIRST test devices

(slide courtesy GSFC, DCL, B. Rauscher)



For simulations, Huff assumes grey curve (for now)

Shape measurement bias comes from scales comparable to galaxy size

• C. Hirata:
$$(\Delta e_1, \Delta e_2) = -\frac{R^4}{F^2} \int \Omega(kR)(\cos 2\phi_k, \sin 2\phi_k) \frac{P_N(k) d^2k}{(2\pi)^2}$$

R = galaxy scale radius; F = total galaxy flux (e-)

Equation based on adaptive moments shape measurement.



Adding persistence to GalSim images

- Define galaxy profile (Sersic) to have unit flux
- Define S/N by amount of white noise added
- Scale XDF P(k) so that total variance is (1 galaxy flux)**2. (assumes domination by galaxies). Rescale again by WFIRST persistence model (1000s delay)
- Add instance of noise from rescaled P(k)
- Measure/compare ellipticities (g1,g2) with total noise to case with white noise only.



Simulated biases from persistence

SN	size	n	<g1 bias=""> <g2 bias=""></g2></g1>
15	0.5"	1	-0.0106 $-0.0076(+/-0.0014) (+/- 0.0014)$
25	0.5"	1	-0.00342 -0.00314 (+/- 0.00085) (+/- 0.00085)
50	0.5"	1	-0.00103 -0.00078 (+/- 0.00042) (+/- 0.00042)
100	0.5"	1	-0.00031 -0.00042 (+/- 0.00065) (+/- 0.00065)
25	1.0"	1	-0.0018 -0.0030 (+/- 0.00082) (+/- 0.00082)

• PRELIMINARY! Realism still being tweaked, but these are not obviously negligible